

INTERNATIONAL BIOMETRIC PERFORMANCE CONFERENCE

Evaluation and Performance of Biometric Technologies



IGD

April 1-3, 2014 **Call for Papers**

NIST, NPL and Fraunhofer IGD invite talks for the IBPC conference on performance and testing of biometric systems. The forum will bring together evaluators, users, technology providers to discuss performance in applications that embed biometric functions or component. The conference is focused on quantitative, applied biometrics, aiming to elicit information that guides policy, design, planning, and implementation of high performance biometric systems, particularly how systems are tested, certified, upgraded and improved. The goal is not to give specific testing results unless the test methods are novel or the results are fundamental to future decisions. The conference specifically invites talks on automated border control (ABC), video-based recognition, security, and emerging biometric uses. The conference aims to advance and expand the use of biometrics by targeting operationally relevant themes, giving emphasis to design, procurement, and what performance data operators require from test and evaluation activities.

Topic area I: Test methods:

Identification systems: metrics, limits, scalability, relation to 1:1 Recognition in video: archival and streaming, multiple persons, cameras Product vs. component tests, certification, interoperability Use of biometrics in early life: Effects of age and ageing Beyond the DET: Novel tests and performance metrics Efficient testing, re-usable testing, frameworks Statistical methods for efficiency, for prediction Desirable, undesirable algorithm properties – 1:1, 1:N and forensics Desirable, undesirable sample properties, and quality estimation Performance of sensors and capture devices Untested, unspoken aspects of performance: what matters, what does not, what's in the noise?

Testing and standardization gaps; testing in academia Usability and accessibility testing for biometrics

Topic area II: Operational aspects

Certification: When is it viable, needed and cost effective How to drive error rates lower: Measurement for control + mitigation Quality of samples and databases. Evaluation / roles of Quality Designing tests as integral parts of operational systems; cloud tests Total system performance and tradeoffs: Accuracy, speed, security,

reliability, usability, interoperability, scalability, assurance, stability How to specify performance in a procurement document Technology vs. scenario vs. operational vs. other tests Realizing multimodal benefits: fusion beyond simple OR Data and its ground-truth: operational vs. laboratory vs. synthetic

Topics area III: Security and privacy aspects Security: risks, priors, costs, fallbacks, evaluation of multifactor auth. Resilience under active attacks (vulnerability, spoofing) Defeat of systems (detection of evasion) Feasibility of common criteria testing of biometric components Privacy enhancing technology, de-identification Remote authentication: Challenges, assurance, testing Template protection and biometric pseudo-identifiers Retrospectives, lessons learned, long term perspective, critical appraisal

of other programs, events, specifications.



Program Committee:

Patrick Grother, Elham Tabassi, NIST, US Tony Mansfield, NPL, UK Christoph Busch, Fraunhofer IGD, DE

Intended speakers:

Research and development staff, system analysts, users, evaluators, planners, writers of technical specifications, standards developers and adopters.

Target audience:

Professionals concerned with biometric system evaluation, procurement, deployment, maintenance, design, configuration, integration, standardization, research and development.

Important dates:

Submission of 1-5 page abstract	
Notification of acceptance	
Submission of slides + papers	
Online registration closes	
Satellite Workshops I: a. Vulnerability assessment b. TBA	
IBPC 2014 Conference	
Satellite Workshops II: TBA	
ril 1-3, 2014	
een Auditorium (cap. 250)	
ST Gaithersburg, MD, USA	
ireless	
ithersburg area hotels, TBA	
IS 175 (estimate) via registration	
Contact the organizers:	
pc2014 AT nist DOT gov	

